

09829136_CLS

Most Frequently Occurring Classifications of Patents Returned
From A Search of 09829136 on July 21, 2003

Original Classifications

8	365/201
5	324/763
3	714/724
2	324/73.1
2	365/200
2	714/718
2	714/726
2	714/727
2	714/736

Cross-Reference Classifications

11	365/201
7	714/733
5	714/718
3	365/236
3	714/726
2	326/16
2	326/39
2	365/185.3
2	365/225.7
2	714/725
2	714/736

Combined Classifications

19	365/201
7	714/718
7	714/733
6	324/763
5	714/726
4	714/736
3	365/200
3	365/236
3	714/724
2	324/73.1
2	326/16
2	326/39
2	365/185.22
2	365/185.3
2	365/189.02
2	365/225.7
2	714/725
2	714/727

09829136_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 09829136 on July 21, 2003

19	365/201	(8 OR, 11 XR)
	Class 365 :	STATIC INFORMATION STORAGE AND RETRIEVAL
	365/189.01	READ/WRITE CIRCUIT
	365/201	.Testing
7	714/718	(2 OR, 5 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/718	.Memory testing
7	714/733	(0 OR, 7 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/733	..Built-in testing circuit (BILBO)
6	324/763	(5 OR, 1 XR)
	Class 324 :	ELECTRICITY: MEASURING AND TESTING
	324/500	FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
	324/537	.Of individual circuit component or element
	324/763	..DUT including test circuit
5	714/726	(2 OR, 3 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/726	..Scan path testing (e.g., level sensitive scan design (LSSD))
4	714/736	(2 OR, 2 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/736	..Device response compared to expected fault-free response
3	365/200	(2 OR, 1 XR)

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	Class	365	:	STATIC INFORMATION STORAGE AND RETRIEVAL
		365/189.01		READ/WRITE CIRCUIT
		365/200		.Bad bit
3	365/236		(0 OR, 3 XR)	
	Class	365	:	STATIC INFORMATION STORAGE AND RETRIEVAL
		365/230.01		ADDRESSING
		365/236		.Counting
3	714/724		(3 OR, 0 XR)	
	Class	714	:	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
		714/699		PULSE OR DATA ERROR HANDLING
		714/724		.Digital logic testing
2	324/73.1		(2 OR, 0 XR)	
	Class	324	:	ELECTRICITY: MEASURING AND TESTING
		324/73.1		PLURAL, AUTOMATICALLY SEQUENTIAL TESTS
2	326/16		(0 OR, 2 XR)	
	Class	326	:	ELECTRONIC DIGITAL LOGIC CIRCUITRY
		326/16		WITH TEST FACILITATING FEATURE
2	326/39		(0 OR, 2 XR)	
	Class	326	:	ELECTRONIC DIGITAL LOGIC CIRCUITRY
		326/37		MULTIFUNCTIONAL OR PROGRAMMABLE (E.G., UNIVERSAL, ETC.)
		326/39		.Array (e.g., PLA, PAL, PLD, etc.)
2	365/185.22		(1 OR, 1 XR)	
	Class	365	:	STATIC INFORMATION STORAGE AND RETRIEVAL
		365/185.01		FLOATING GATE
		365/185.18		.Particular biasing
		365/185.2		..Reference signal (e.g., dummy cell)
		365/185.22		...Verify signal
2	365/185.3		(0 OR, 2 XR)	
	Class	365	:	STATIC INFORMATION STORAGE AND RETRIEVAL
		365/185.01		FLOATING GATE
		365/185.18		.Particular biasing
		365/185.29		..Erase
		365/185.3		...Over erasure
2	365/189.02		(1 OR, 1 XR)	
	Class	365	:	STATIC INFORMATION STORAGE AND RETRIEVAL
		365/189.01		READ/WRITE CIRCUIT
		365/189.02		.Multiplexing

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2  365/225.7      (0 OR, 2 XR)
    Class  365 :  STATIC INFORMATION STORAGE AND RETRIEVAL
    365/189.01    READ/WRITE CIRCUIT
    365/225.7     .Having fuse element

2  714/725        (0 OR, 2 XR)
    Class  714 :  ERROR DETECTION/CORRECTION AND FAULT
                  DETECTION/RECOVERY
    714/699       PULSE OR DATA ERROR HANDLING
    714/724       .Digital logic testing
    714/725       ..Programmable logic array (PLA) testing

2  714/727        (2 OR, 0 XR)
    Class  714 :  ERROR DETECTION/CORRECTION AND FAULT
                  DETECTION/RECOVERY
    714/699       PULSE OR DATA ERROR HANDLING
    714/724       .Digital logic testing
    714/726       ..Scan path testing (e.g., level sensitive sca
n
                  design (LSSD))
    714/727       ...Boundary scan

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09829136_LIST

PLUS Search Results for S/N 09829136, Searched July 21, 2003

5768289
5970005
5826007
5377199
5968192
6044481
4920515
6163867
4951254
5216746
5946246
6032140
6119252
6175529
6178124
4175286
4385275
4458338
4462029
4588907
4601034
4816757
4855670
4885748
4887268
4912395
4918379
4965800
5177745
5210448
5247481
5291448
5309444
5369647
5455517
5471429
5473229
5514975
5537053
5559744
5563830
5594689
5631912
5675540
5682389
5694611

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5703495
5703789
5710779
5723990

09829136_QUAL

5768289 99
5970005 99
5826007 88
5377199 88
5968192 87
6044481 87
4920515 87
6163867 87
4951254 87
5216746 87
5946246 87
6032140 87
6119252 87
6175529 87
6178124 87
4175286 86
4385275 86
4458338 86
4462029 86
4588907 86
4601034 86
4816757 86
4855670 86
4885748 86
4887268 86
4912395 86
4918379 86
4965800 86
5177745 86
5210448 86
5247481 86
5291448 86
5309444 86
5369647 86
5455517 86
5471429 86
5473229 86
5514975 86
5537053 86
5559744 86
5563830 86
5594689 86
5631912 86
5675540 86
5682389 86
5694611 86
5703495 86
5703789 86

09829136_QUAL

5710779 86
5723990 86